

REMARKSSummary of Office Action

Claims 1-21 are pending. Claims 10-21 were withdrawn from consideration as drawn to a non-elected invention.

Claims 1-9 have been rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent No. 6,124,725 to Sato ("Sato").

Applicants' Reply

Applicants respectfully traverse the prior art rejections of claims 1-9.

Applicants resubmit the Remarks presented in the previous Reply (dated January 12, 2006), which for brevity are not reproduced but are incorporated by reference herein.

Applicants request kind reconsideration of those Remarks.

Applicants have read Sato carefully, and again respectfully submit that Sato does not teach, show or suggest the elements of claim 1, namely (1) accelerating a substrate while in contact with the contact needles and/or (2) measuring the electrical characteristics of an accelerating substrate. Sato's testing is carried out only when the chuck, probes and wafer W are stationary. (See e.g., col. 9 lines 21-24 "the main chuck 11 is brought to a halt"). Applicants believe the Examiner mistakenly concludes that "[t]herefore, Sato does show measuring the electrical characteristics of the circuit elements during mechanical acceleration of the mounted semiconductor substrate when it is in contact with the contact needles).

For at least the foregoing reasons, claim 1 and also dependent claims 2-9 are patentable over Sato.

Conclusion

PATENT

Applicants respectfully submit that this application is now in condition for allowance. Reconsideration and prompt allowance of which are respectfully requested. If there are any remaining issues to be resolved, applicants respectfully request that the Examiner kindly contact the undersigned attorney for early resolution.

Respectfully submitted,

By: 

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